



ENGINEERING DEPT.		PRODUCT SPECIFICATION For CSIM Series SIM Card Connector	SPEC.NO.: SPCSIM08B
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1. SCOPE:

This specification covers the requirements for product performance and test methods of the SIM Card Product shall be of the design, construction and physical dimensions specified in the applicable product drawing

2. APPLICABLE STANDARDS:

MIL - STD - 202	Methods for test of connectors for electronic equipment
EIA-364	Test methods for electrical connectors

3. APPLICABLE SERIES NO.: CSM30621D02-LF

4. SHAPE, CONSTRUCTION AND DIMENSIONS

See attached drawings

5. ACCOMMOATED P.C.BOARD

See attached drawings

CVILUX

REVIEWED : Eisley APPROVED : Sun VERIFIED : Jessie .

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7. ELECTRICAL PERFORMANCE:

	ITEN	TEST CONDITION	REQUIREMENT
7.1	Rated current and voltage		0.5A, 5.5V AC/DC max. (r.m.s.)
7.2	Contact resistance	EIA-364-23 Mate card measured dry circuit, 20 mV , 100mA max.	100mΩ max.
7.3	Dielectric strength	EIA-364-20 Apply 250V AC for 1 minute between adjacent terminals and ground.	No Breakdown.
7.4	Insulation Resistance	EIA-364-21 Apply 500V DC between adjacent pins or pin and ground.	1000MΩ min.

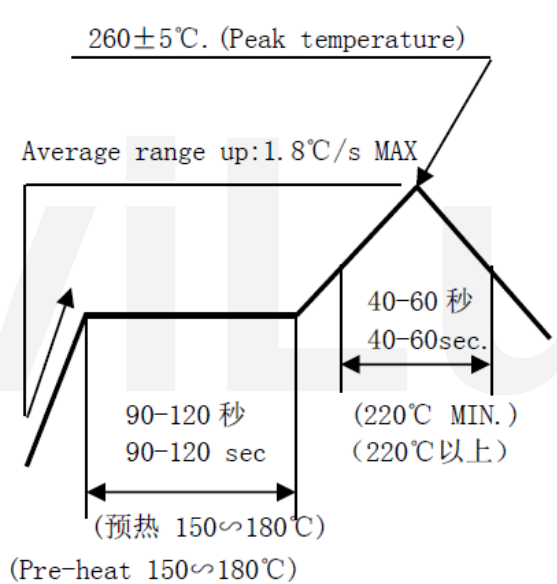
8. MECHANICAL PERFORMANCE:

	ITEN	TEST CONDITION	REQUIREMENT
8.1	Durability	EIA-364-09C Insertion and extraction are repeated 5000 cycles with the card at the speed rate of 400- 600 cycles/hour. As for tray type connector, must test 3000 cycles by hand.	Appearance: No damage Contact Resistance Less than 140mΩ

9. ENVIRONMENTAL PERFORMANCE:

	ITEN	TEST CONDITION	REQUIREMENT
9.1	Vibration	Eia-364-28D Mate card and subject to the following vibration conditions, for a period of 2 hours in each of 3 mutually perpendicular axes, passing DC 1 mA during the test Amplitude: 1.50 mm p-p or 19.6m/s ² (2G) Frequency: 10-55-10 Hz Shall be traversed in 1 minute.	Appearance: No damage Contact Resistance Less than 140mΩ Discontinuity 0.1micro sec. Max.
9.2	Humidity	EIA-364-31A Temperature: 40 ± 2℃ Humidity: 90% (RH) Period: 96 hour	Appearance: No damage Contact Resistance Less than 140mΩ

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	ITEN	TEST CONDITION	REQUIREMENT
9.3	Solder ability	EIA-364-52 Soldering time: 10 second Soldering pot: $245 \pm 5^{\circ}\text{C}$	Minimum: 95% of immersed area
9.4	Resistance to soldering heat	(1) Reflow part $260 \pm 5^{\circ}\text{C}$ Peak 220°C Min., 40~60sec (2) Pre heat part $150 \sim 180^{\circ}\text{C}$, 90~120sec. * Refer to reflow temperature profile.  260±5°C. (Peak temperature) Average range up: 1.8°C/s MAX 40-60 秒 40-60sec. (220°C MIN.) (220°C 以上) 90-120 秒 90-120 sec (预热 150~180°C) (Pre-heat 150~180°C)	No physical damage shall occur.
9.5	Heat aging	EIA-364-17 Leave the connector in a test chamber at 85°C for 96hours, measure the sample before the start of test and after completion outside the chamber for between one and two hours	Appearance: No damage Contact Resistance Less than $140\text{m}\Omega$ Insulation Resistance: $1000\text{M}\Omega$ min.
9.6	Cold aging	EIA-364-17 Leave the connector in a test chamber at -40°C for 96 hours measure the sample before the start of the and after completion. Outside the chamber for between one and two hours water drops shall be removed	Appearance: No damage Contact Resistance Less than $140\text{m}\Omega$ Insulation Resistance: $1000\text{M}\Omega$ min.

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	ITEN	TEST CONDITION	REQUIREMENT
9.7	Salt Spray	Temperature: $35 \pm 3^{\circ}\text{C}$ Solution: $5 \pm 1\%$ Spray time: 48 ± 4 hours (Stamping before plated) Spray time: 24 ± 4 hours (Stamping after plated) Mate connectors and expose to the following salt mist conditions. Upon completion of the exposure period, salt deposits shall be removed by a gentle wash or dip in running water and dried naturally, after which the specified measurements shall be performed. The specimens shall be suspended from the top using waxed twine, string or nylon thread. The test only define the plating area, without plating area (as copper cross section) will not be defined. (EIA 364-26B / MIL-STD-202 Method 101)	Appearance: No damage Contact resistance: Less than twice of initial

10. OPERATING TEMPERATURE RANGE: $-30^{\circ}\text{C} \sim 85^{\circ}\text{C}$